

Defect-oriented fault simulation and test generation in digital circuits

Kuzmicz, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** IEEE ISQED 2001 : proceedings of the IEEE 2001 2nd International Symposium on Quality Electronic Design : March 26-28, 2001, San Jose, California 2001 / p. 365-371
<https://ieeexplore.ieee.org/document/915257>